AF/IFW PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

AUG 07 2006 W

Applicants: Young Sun Hwang et al.

Serial No.: 10/719,083

Filed: November 21, 2003

For: Methods for Forming Fine Photoresist Patterns

Group Art Unit: 1765

Examiner: Patricia Ann George

Confirmation No. 2261

I hereby certify that this paper and the documents referred to as enclosed therewith are being deposited with the United States Postal Service as first class mail, postage prepaid, on August 2, 2006, in an envelope addressed to MS Amendments, Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450

Reg. No. 28,491 Attorney for Applicant

AMENDMENT "B" AFTER FINAL REJECTION

MS Amendment Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

Dear Sirs:

Please amend this application as follows:

the amendment to the claims section (along with a complete listing of claims) begins on page 2 of this paper;

the remarks section begins on page 5 of this paper.